

**Notice of References Cited**

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Applicant(s)/Patent Under

Reexamination

ABEDI, SAIED

Examiner

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Art Unit

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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0080719 A1	06-2002	Parkvall et al.	370/235
*	B US-2003/0169709 A1	09-2003	Oki, Noboru	370/335
*	C US-2003/0166408 A1	09-2003	Zhang et al.	455/522
*	D US-2003/0103514 A1	06-2003	Nam et al.	370/412
*	E US-2002/0094778 A1	07-2002	Cannon et al.	455/41
*	F US-2004/0196804 A1	10-2004	Love et al.	370/329
*	G US-2003/0185155 A1	10-2003	Huang et al.	370/235
*	H US-7,403,892 B2	07-2008	Sjoberg et al.	704/201
*	I US-6,047,000	04-2000	Tsang et al.	370/412
*	J US-6,728,208 B1	04-2004	Puuskari, Mikko	370/230.1
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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V	
W	
X	

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